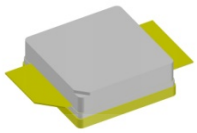
GaN Power Transistors IE36085W

Product Features

- 3400~3600MHz
- 85W Saturated Power @ 48V
- 68% Drain Efficiency @ Psat
- 35% Drain Efficiency @ 42.8dBm

Applications

- WiMAX, LTE, WCDMA, GSM
- Multi-Band, Multi-Mode
- Multi-Carrier
- High Efficiency, Doherty Amplifier



Package Type : RF12002KR3

Typical Single-Carrier LTE Performance (V_{DS}= +48V, T_C=25℃, 50Ω)

Frequency [MHz]	Peak Power		Average Power*1			
	Power [W]	Drain Efficiency [%]	Power [W]	Gain [dB]	Drain Efficiency [%]	ACLR [dBc]
3405.0	105.0	70.5	19	17.1	34.8	-32.0
3480.0	96.6	70.9	19	17.3	35.4	-30.2
3555.0	86.3	68.4	19	16.6	35.9	-29.5

Note

*1 Measured in the IE36085W test board amplifier circuit, under LTE 10MHz, PAR 7.5dB @0.01% probability on CCDF.

Absolute Maximum Ratings

Rating	Symbol	Value	Unit	Condition
Drain to Source Voltage	V_{DSS}	150	V	Tc=25℃
Gate to Source Voltage	V_{GS}	-10, +2	V	Tc=25℃
Operating Voltage	V_{DD}	52	V_{DC}	-
Maximum Forward Gate Current	I_{GMAX}	12	mA	Tc=25℃
Maximum Drain Current*1	I_{DMAX}	4.5	A	Tc=25℃
Power Dissipation	P_{DISS}	48	W	Tc=85℃
Storage Temperature	T_{STG}	-65, +150	℃	-
Case Operating Temperature	T_C	-40, +150	℃	30 seconds
Operating Junction Temperature*2	T_J	225	℃	-
Soldering Temperature*3	T_S	245	℃	-

Note

*1 Current Limit for long term, reliable operation.

*2 Continuous use at maximum temperature will affect MTTF.

*3 Refer to the Application Note(AN-002) on soldering - "Solder Condition for RFHIC's GaN Device"

Thermal Characteristics

Rating	Symbol	Value	Unit	Condition
Thermal Resistance, Junction to Case	$R_{\theta JC}$	2.90 *1	℃/W	Tc=85℃

Note

*1 Measured for the IE36085W at dissipation power of 48.3W.

Electrical Characteristics (T_C=25℃ unless otherwise noted)

Characteristics	Conditions	Symbol	Min	Typ	Max	Unit
DC Characteristics[*1]						
Gate Threshold Voltage	**V_{DS} = 10V** **I_D = 10.8mA**	$V_{GS(TH)}$	-3.8	-3.0	-2.3	V_{DC}
Gate Quiescent Voltage	**V_{DS} = 48V** **I_D = 350mA**	$V_{GS(Q)}$	-	-2.6	-	V_{DC}
Saturated Drain Current[*2]	**V_{DS} = 6V** **V_{GS} = 2V**	I_{DS}	9.0	10.8	-	A
Drain-Source Breakdown Voltage	**V_{GS} = -8V** **I_D = 10.8mA**	V_{BR}	150	-	-	V
Gate Leakage Current	**V_{GS} = -8V** **V_{DS} = 120V**	I_{GLKG}	-2.4	-	-	mA
Drain Leakage Current	**V_{GS} = -8V** **V_{DS} = 120V**	I_{DLKG}	-	-	4.3	mA
RF Characteristics (Fc=3480MHz unless otherwise noted)						
Saturated Output Power[*3,6]	**V_{DS} = 48V** **I_{DQ} = 350mA**	P_{SAT}	-	85.0	-	W
Pulsed Drain Efficiency[*3]	**V_{DS} = 48V** **I_{DQ} = 350mA** **P_{OUT} = P_{SAT} Pulsed**	η	64.0	68.0	-	%
Modulated Gain[*4]	**V_{DS} = 48V** **I_{DQ} = 350mA** **P_{OUT} = 42.8dBm**	G_{BR}	15.5	16.5	-	dB
LTE Linearity[*4]	**V_{DS} = 48V** **I_{DQ} = 350mA** **P_{OUT} = 42.8dBm**	ACLR	-	-26.0	-24.0	dBc
Modulated Drain Efficiency[*4]	**V_{DS} = 48V** **I_{DQ} = 350mA** **P_{OUT} = 42.8dBm**	η	32.0	35.0	-	%
Output Mismatch Stress[*3, 5]	**V_{DS} = 48V** **I_{DQ} = 350mA** **P_{OUT} = P_{SAT} Pulsed**	VSWR	-	-	10:1	ψ

Note

*1 Measured on wafer prior to packaging.

*2 Scaled from PCM data.

*3 Pulse width 100μsec, Duty Cycle 10%.

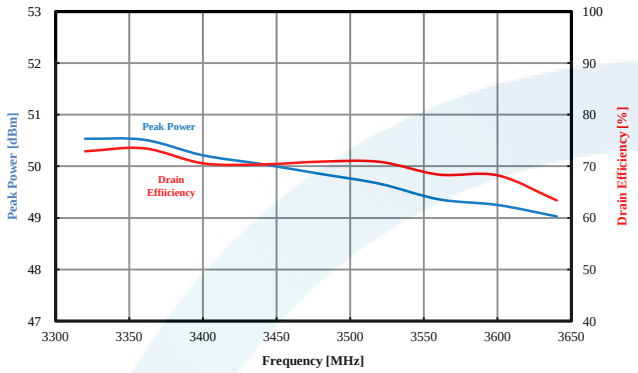
*4 Measured in the IE36085W test board amplifier circuit, under LTE 10MHz, PAR7.5dB @0.01% probability on CCDF.

*5 Measured in the IE36085W test board amplifier circuit. No damage at all phase angles.

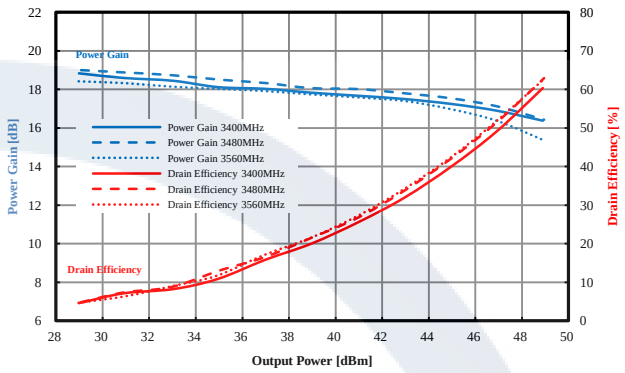
*6 Psat is defined as ΔPout/ΔPin<0.1, where ΔPin is increased input power, ΔPout is increased output power.

Typical Pulsed Signal Performance (Tc=25℃, Measured in the IE36085W test board amplifier circuit)

Peak Power, Drain Efficiency vs. Frequency



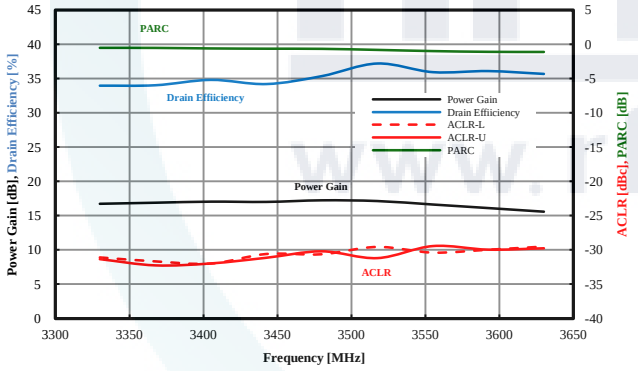
Pulsed Power Gain, Drain Efficiency vs. Output Power



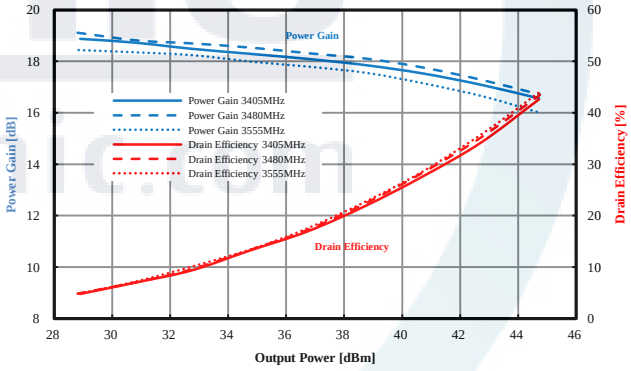
V_{DS} = 48V, I_{DQ} = 350mA, Pulse Width = 100μsec, Duty Cycle = 10%

Typical LTE Signal Performance (Tc=25℃, Measured in the IE36085W test board amplifier circuit)

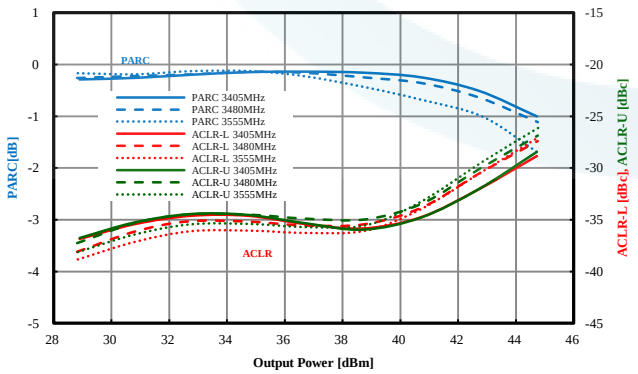
LTE Power Gain, Drain Efficiency, ACLR, PARC vs. Frequency



Power Gain, Drain Efficiency vs. Output Power



PARC, ACLR vs. Output Power

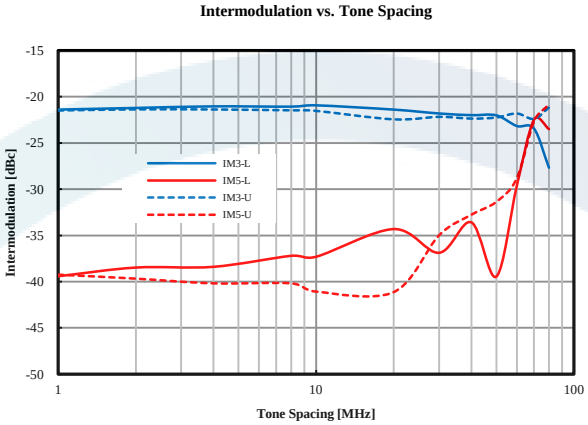


P_{AVG} = 42.8dBm, V_{DS} = 48V, I_{DQ} = 350mA

LTE 10MHz BW, PAPR=7.5dB @ 0.01% Probability on CCDF

Typical 2-tone Intermodulation Imbalance Performance

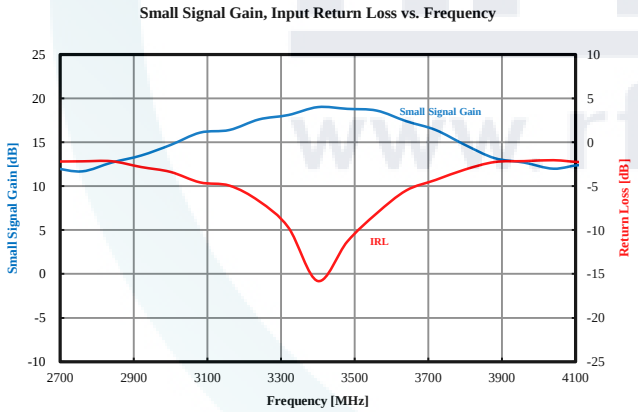
(Tc=25℃, Measured in the IE36085W test board amplifier circuit)

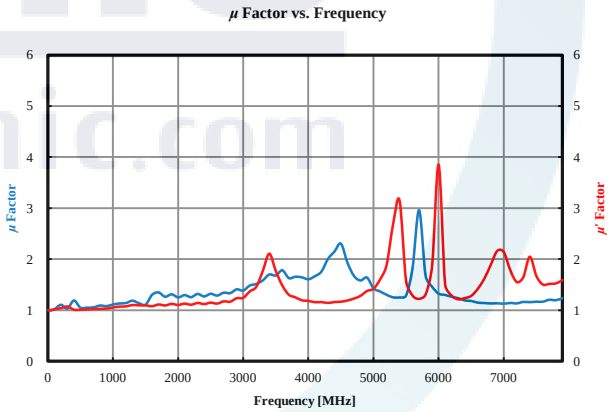


2-tone Power = 47.3dBm, V_{DS} = 48V, I_{DQ} = 350mA

Typical Small Signal Performance

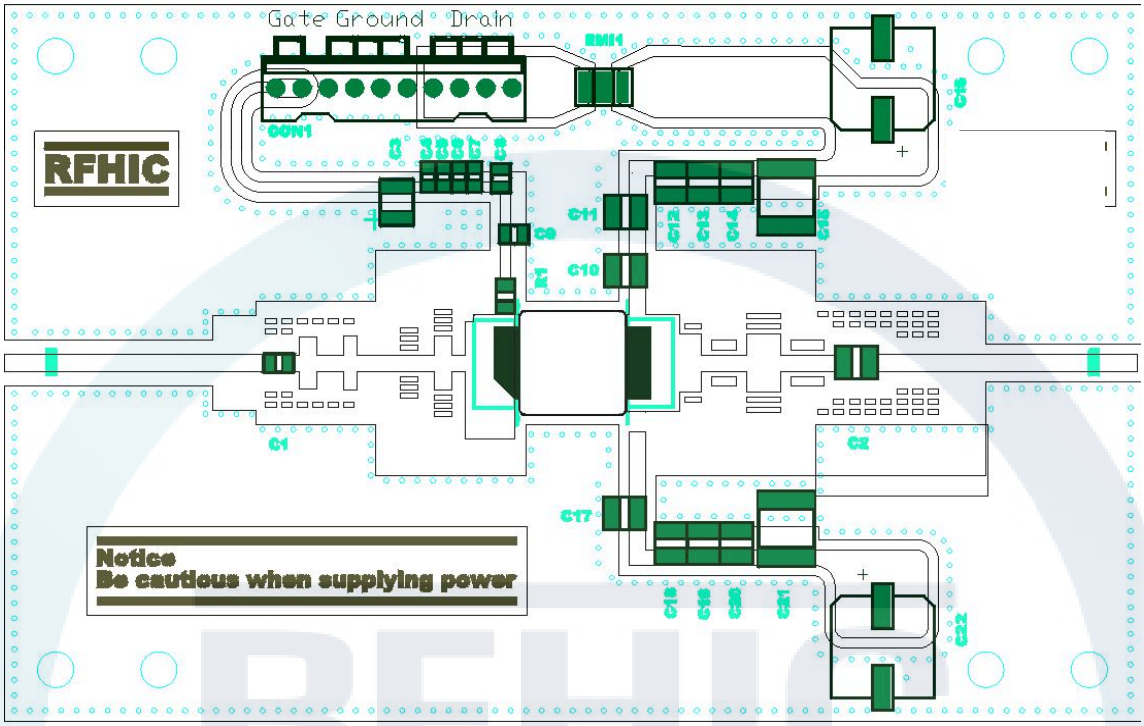
(Tc=25℃, Measured in the IE36085W test board amplifier circuit)





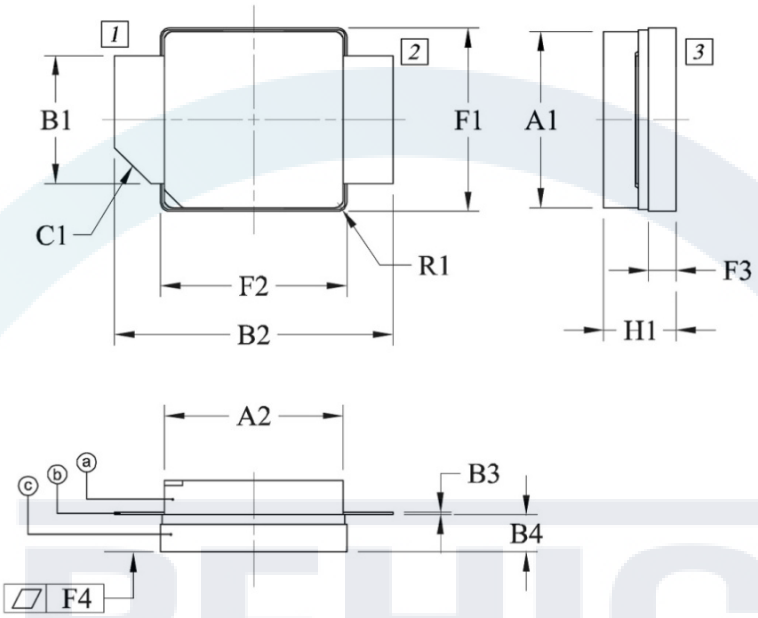
P_{IN} = 0dBm, V_{DS} = 48V, I_{DQ} = 350mA

Test Board Component Layout



Part	Description	Part Number	Manufacturer
R1	10 ohm Chip Resistor	MCR10EZPJ100	ROHM
C1	3.9pF High Q Capacitor	201CHA3R9CSLE	TEMEX
C2	3.9pF High Q Capacitor	501CHB3R9CSLE	TEMEX
C3	4.7uF Tantalum Capacitor	TAJA475K025RNJ	AVX
C4	10nF Chip Capacitor	GRM188R71H103KA01D	MURATA
C5	1nF Chip Capacitor	GRM188R71H102KA01D	MURATA
C6	100pF Chip Capacitor	GRM1885C1H101JA01D	MURATA
C7	10pF Chip Capacitor	GRM1885C1H100JA01D	MURATA
C8,C11,C14	-	-	-
C17~C22	-	-	-
C9	5.6pF High Q Capacitor	201CHA5R6CSLE	TEMEX
C10	5.6pF High Q Capacitor	501CHB5R6CSLE	TEMEX
C12	39pF High Q Capacitor	501CHB390JSLE	TEMEX
C13	100pF High Q Capacitor	501CHB101JSLE	TEMEX
C15	10uF MLCC	RS80R2A106M	MARUWA
C16	33uF Aluminum Capacitor	BDS100VC33MJ10TP	SAMYOUNG
EMI1	EMI FILTER	CTH32R102S20A-TM	MARUWA
CON1	DC Connector	5045-10	MOLEX
PCB	εr=3.48 ± 0.05, 0.030” (0.762mm)	RO4350B	ROGERS Corp.
TR	85W GaN Transistor	IE36085W	RFHIC

Package Dimensions (Type:RF12002KR3)



Pin Description	
Pin No	Function
1	Gate
2	Drain
3	Source

ⓐ- Lid
ⓑ- Lead Frame
ⓒ- Flange

Dim.	INCH			MILLIMETER		
	MIN	TYP	MAX	MIN	TYP	MAX
A1	.380	.384	.390	9.65	9.75	9.90
A2	.380	.384	.390	9.65	9.75	9.90
B1	.274	.280	.285	6.97	7.10	7.23
B2	.579	.598	.618	14.70	15.20	15.70
B3	.004	.005	.007	0.10	0.13	0.18
B4	.058	.063	.068	1.48	1.60	1.73
C1 (Chamfer)	.075	.079	.083	1.90	2.00	2.10
F1	.395	.400	.405	10.03	10.16	10.29
F2	.395	.400	.405	10.03	10.16	10.29
F3	-	-	-	-	-	-
F4	-	.001	-	-	0.03	-
H1	.118	.126	.138	3.00	3.20	3.50
L1	-	-	-	-	-	-
L2	-	-	-	-	-	-
R1 (Radius)	.016	.020	.024	0.40	0.50	0.60

Revision History

Part Number	Release Date	Version	Description	Data Sheet Status
IE36085W	March, 2016	1.2	Modified Electrical Characteristics	-
IE36085W	June, 2015	1.1	Modified Test Fixture	-
IE36085W	May, 2015	1.0	Initial Release of Data sheet	-

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